

MDM1200E17D

FEATURES

- * Low noise due to ultra soft fast recovery diode.
- * High reliability, high durability diodes.
- * Isolated heat sink (terminal to base).

ABSOLUTE MAXIMUM RATINGS (T_C=25°C)

Item	Symbol	Unit	MDM1200E17D
Repetitive Peak Reverse Voltage	V _{RRM}	V	1,700
Forward Current	DC	A	1,200
	1ms		2,400
Operating Junction Temperature	T _{vj op}	°C	-40 ~ +125
Storage Temperature	T _{stg}	°C	-40 ~ +125
Isolation Test Voltage	Terminals-base	V _{ISO}	V _{RMS}
	Terminal 1-Terminal 2	V _{ISO T-T}	
Screw Torque	Terminals (M8)	-	15 (1)
	Mounting (M6)	-	6 (2)

Notes: (1) Recommended Value 15⁺⁰₋₃N·m

(2) Recommended Value 5.5±0.5N·m

ELECTRICAL CHARACTERISTICS

Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions
Repetitive Reverse Current	I _{RRM}	mA	-	1.0	10.0	V _{AK} =1,700V, T _{vj} =125°C
Forward Voltage Drop	V _F	V	1.8	2.1	2.5	I _F =1,200A, T _{vj} =125°C
Reverse Recovery Time	t _{rr}	μs	-	0.5	-	V _{CC} =900V, I _F =1,200A, L _S =100nH R _G =1.5Ω, C _{GE} =120nF (3)(Fig.1) T _{vj} =125°C (Type test)
Reverse Recovery Loss	E _{rr(10%)}	J/P	-	0.4	-	
Reverse Recovery Time(2)	t _{rr(2)}	μs	-	0.5	1.0	V _{CC} =900V, I _F =2,400A, L _S =70nH R _G =1.5Ω, T _{vj} =125°C (4)(Fig.1)
Reverse Recovery Loss(2)	E _{rr(10%)(2)}	J/P	-	0.8	1.2	(Routine test)

Notes: (3) Counter arm: MBN1200E17D V_{GE}= ±15V

(4) Counter arm: MBN2400E17D V_{GE}= ±15V

R_G and C_{GE} value are the test condition's value to define the switching characteristics not recommended value.

Please, determine the suitable R_G and C_{GE} value after the measurement of switching waveforms (overshoot voltage, etc.) with appliance mounted.

PACKAGE CHARACTERISTICS

Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions
Terminal Resistance	R _{CE}	mΩ	-	0.2	-	T _c =25°C, per arm
Stray inductance module	L _{SCE}	nH	-	21	-	per arm
Thermal Impedance	R _{th(j-c)}	K/W	-	-	0.033	Junction to case (par arm)
Contact Thermal Impedance	R _{th(c-f)}	K/W	-	0.008	-	Case to fin (par module)

* Please contact our representatives at order.

* For improvement, specifications are subject to change without notice.

* For actual application, please confirm this spec sheet is the newest revision.

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DEFINITION OF TEST CIRCUIT

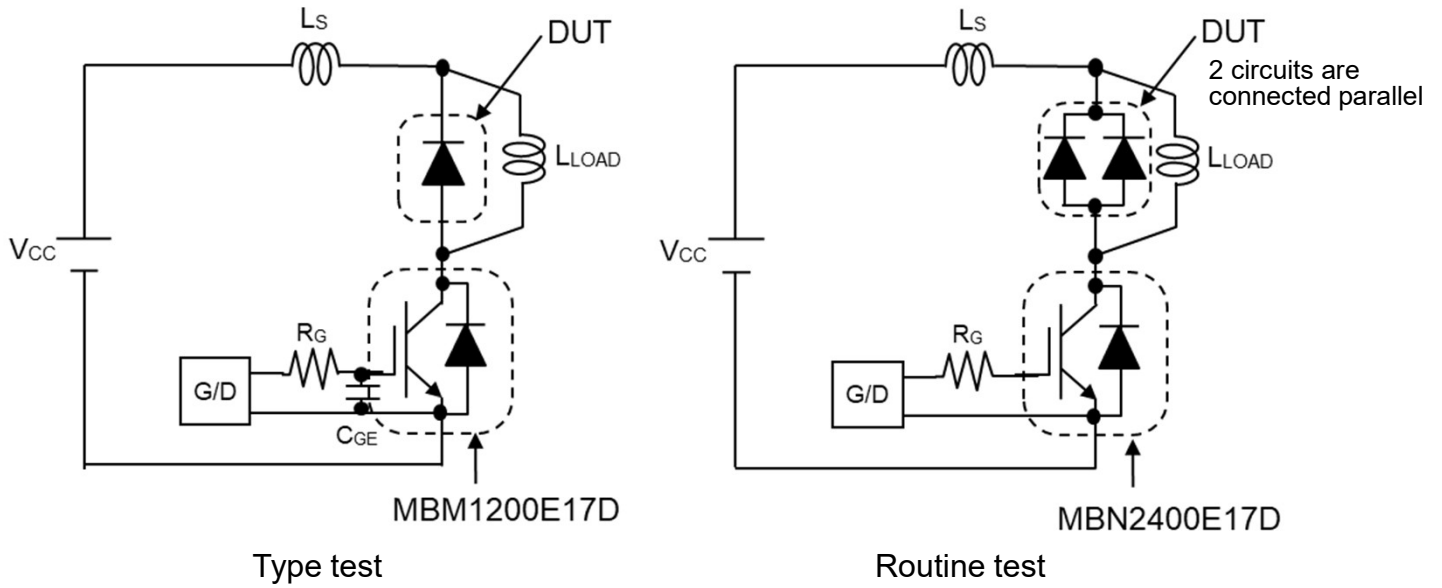


Fig.1 Switching test circuit

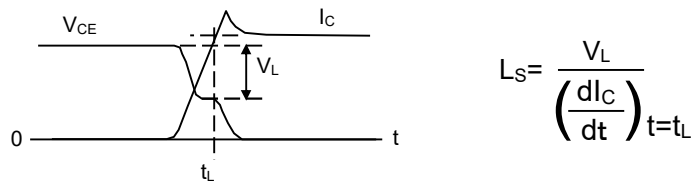
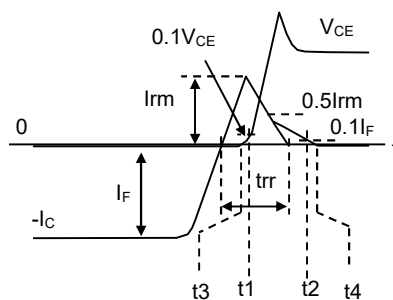


Fig.2 Definition of stray inductance

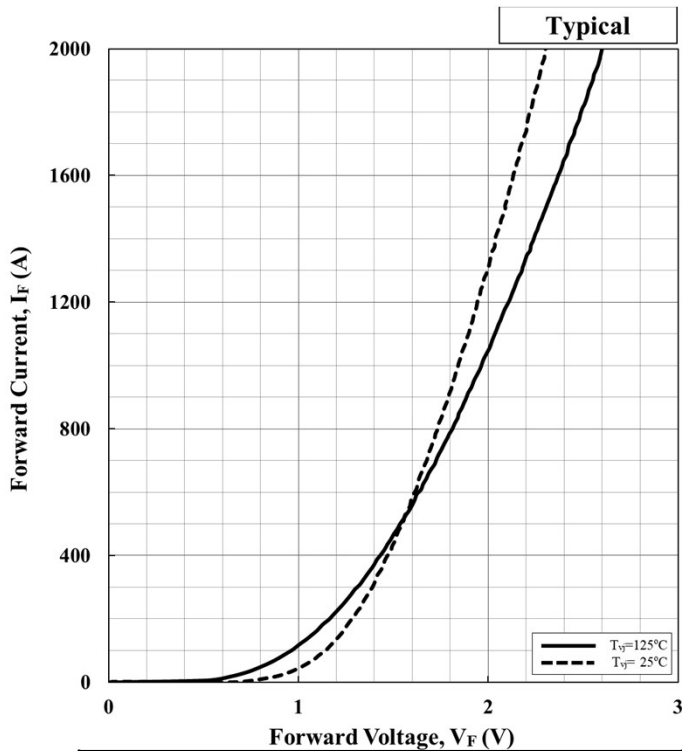


$$E_{rr(10\%)} = \int_{t1}^{t2} I_F \cdot V_{CE} dt$$

$$E_{rr(full)} = \int_{t3}^{t4} I_F \cdot V_{CE} dt$$

Fig.3 Definition of switching loss

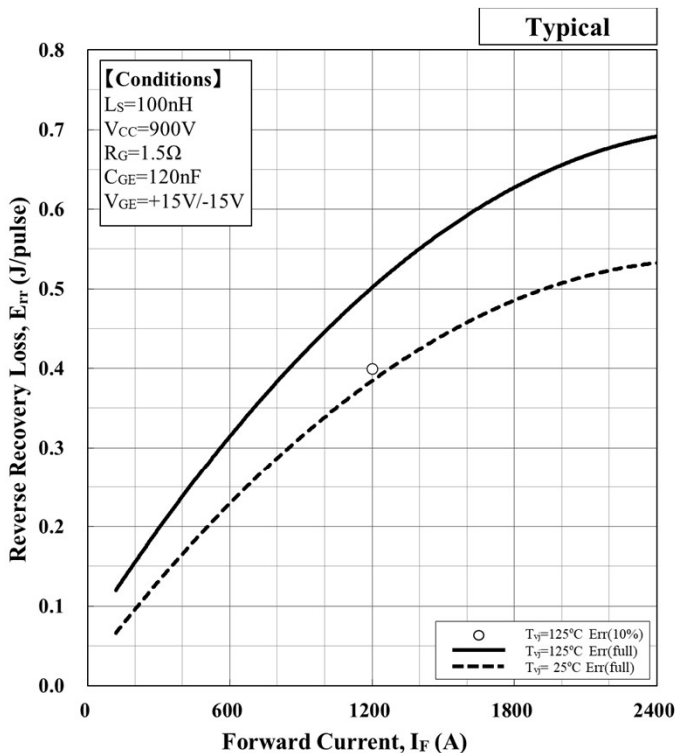
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$$V_F[V] = a_3 \cdot |I_F|^3 + a_2 \cdot |I_F|^2 + a_1 \cdot |I_F| + a_0$$

Temp.[°C]	a_3	a_2	a_1	a_0
25	1.12E-10	-4.97E-07	1.18E-03	1.06E+00
125	1.60E-10	-7.19E-07	1.69E-03	8.44E-01

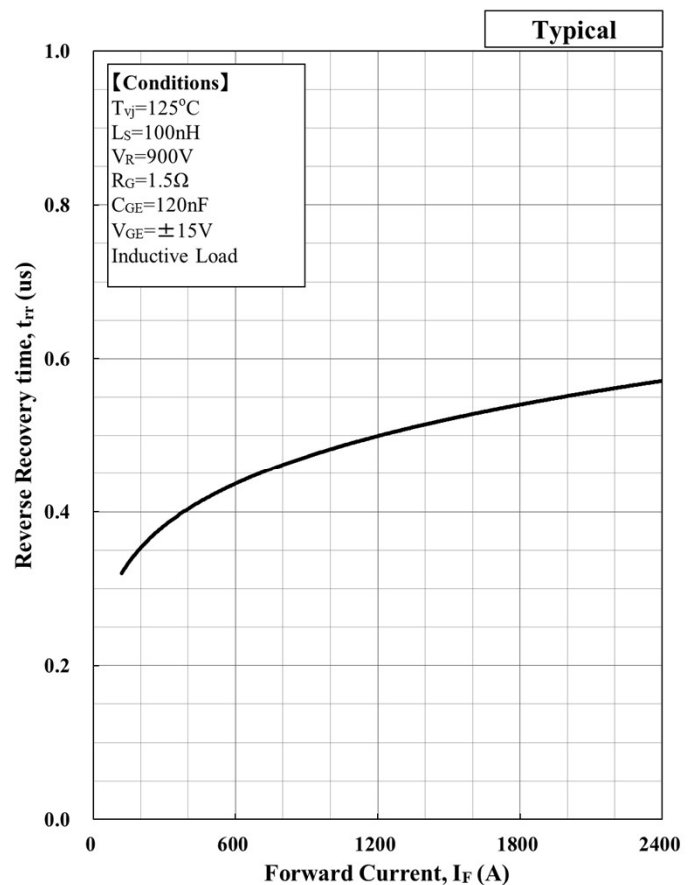
Forward Current vs. Forward Voltage
(Measured at main terminal)



$$E [J] = a_3 \cdot |I_F|^3 + a_2 \cdot |I_F|^2 + a_1 \cdot |I_F| + a_0$$

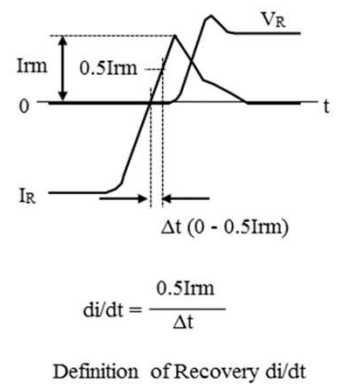
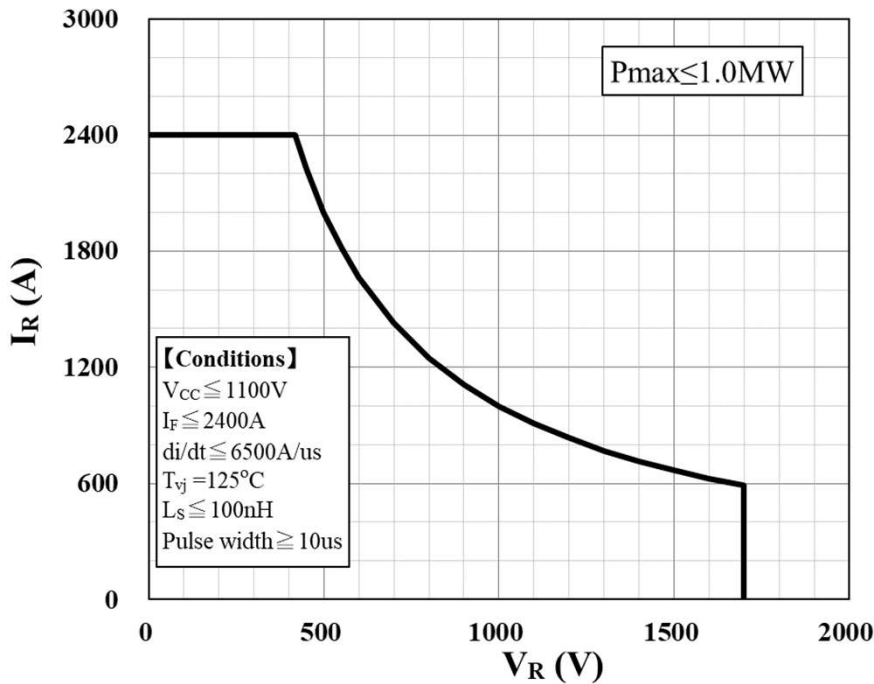
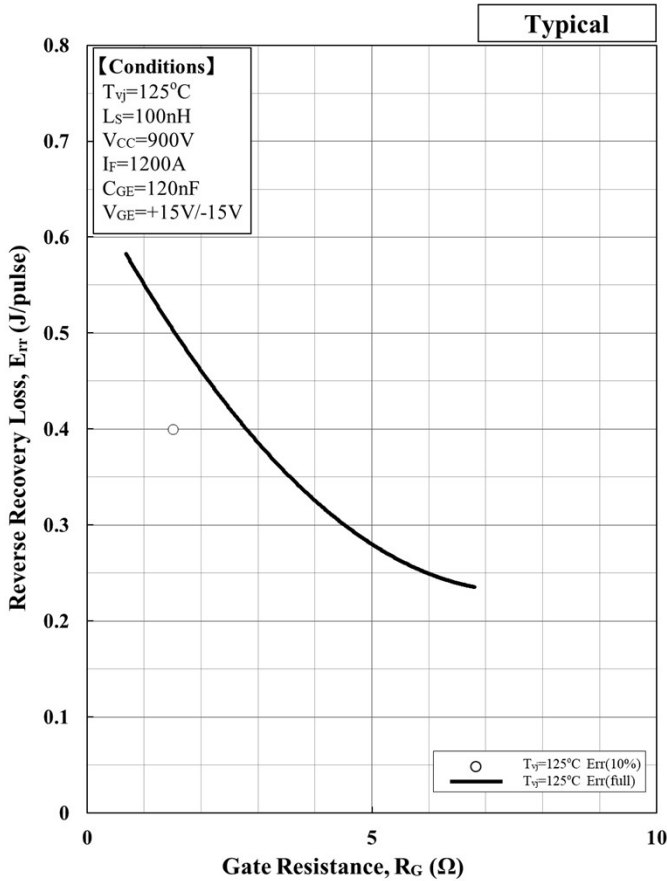
Temp.[°C]	a_3	a_2	a_1	a_0
25	-	-7.50E-08	3.94E-04	2.00E-02
125	-	-8.55E-08	4.66E-04	6.53E-02

Recovery loss vs. Forward current



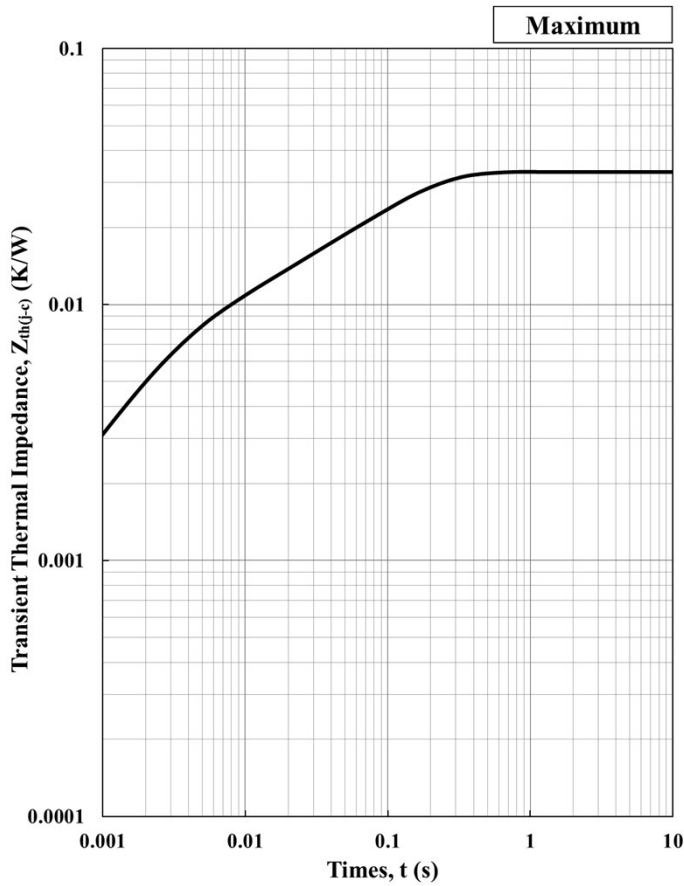
Reverse Recovery time vs. Forward Current

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Reverse Recovery Safe Operation Area (RRSOA)

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Transient Thermal Impedance Curve

Foster model lumped circuit constant

n	1	2	3	4	Unit
R th, Diode [n]	2.10E-02	5.17E-03	6.21E-03	5.83E-04	[K/W]
C th, Diode [n]	5.88E+00	2.82E+00	4.03E-01	5.42E-01	[J/K]

Cauer model lumped circuit constant

n	1	2	3	4	Unit
R th, Diode [n]	3.43E-03	6.35E-03	8.78E-03	1.44E-02	[K/W]
C th, Diode [n]	2.06E-01	2.17E-01	2.11E+00	5.45E+00	[J/K]

Material declaration

Please note the following materials are contained in the product, in order to keep characteristic and reliability level.

Material	Contained part
Lead (Pb) and its compounds	Solder

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8. For handling other than described in this manual, follow the handling instructions (IGBT-HI-00002).

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- For inquiries relating to the products, please contact nearest representatives that is located "Inquiry" portion on the top page of a home page.
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